2011 Defense Working Group December 7, 2011 Williamsburg, VA

JENTEK Sensors, Inc.

Inspection of Shot Peened Engine Components in Regions with Fretting Damage

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7 December 2011





MWM sensors and MWM-Arrays covered by issued and pending patents, including, but not limited to: 5,793,206; 5,966,011; 6,144,206; 6,188,218 B1; 6,198,279 B1; 6,727,691 B2; 6,995,557 B2; 6,992,482 B2; 6,952,095 B1; 6,798,198 B2; 6,784,662 B2; 6,781,387 B2; 7,188,532 B2; 7,183,764 B2; 7,161,351 B2; 7,161,350 B2; 7,106,055 B2; 7,095,224, B2; 7,049,811 B2; 6,657,429 B1; 6,486,673 B1; 6,420,876; 6,380,747 B1; 6,377,039; 6,351,120 B1; RE39,206 E.



Outline

- Technology Overview
- Disk Slot Inspection
- Blade Dovetail Inspection
- Cracks at Edges
- Bolt Hole Inspection
- Adaptive Life Management and Risk Assessment
- Optional Baseline Subtraction



Patents Issued and Pending

JENTEK Sensors, Inc.

Technology Overview

Patented IDED sensor and IDED-Arrays

Sensors, Systems, Software, and Algorithms



GridStation® Systems

Current Sensor

Portable and Hand-Held versions



GS-HandHeld (GS-HH)



GridStation[®] Software using Hyperlattices[™]

Performs multivariate inverse methods – i.e. fast. autonomous data analysis for decision support in NDT, CBM and SHM

Fuzzy-Hyperlattices

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Remaining Useful Life Prediction (RUL) and rapid uncertainty estimation



"Air" Calibration Improves Robustness & Ease of Use



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Grid Methods Automatically Rescales Crack Response with Lift-Off Variation



Therefore C-Scan Image Threshold is Independent of Lift-off

Patents Issued and Pending

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Independent Conductivity and Lift-off Imaging

 Grid Methods convert impedance into conductivity and lift-off at each point in the image



Patents Issued and Pending

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Automated Blade Dovetail Inspection Engine Components at FRC-SE Jacksonville, FL



Automated Blade Dovetail Inspection

Inspect for cracks (goal: 0.015 in. x 0.008 in.)



MWM-Array FA57

Patents Issued and Pending

Sensor Coverage

20

Automated MWM-Array Blade Dovetail Inspection

Sensor position at edge of dovetail



Sensor position halfway down dovetail





MWM-Array Sensor

Blade Dovetails

MWM-Array Probe

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Patents Issued and Pending

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Conductivity/Lift-off Measurement Grid

Blade Dovetail Inspection



Filtered MWM-Array Results

Note:

Training Set Blade "with Known Cracks"

Convex Side

Results with Lower Threshold*

Concave Side



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Filtered MWM-Array Results

Note:

Training Set Blade Identified Prior to MWM-Array Inspection as Having "No Cracks"



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Detection of Cracks at Edges with GridStation Edge Location Correction

Conductivity/Lift-Off Images (Unfiltered)



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Detection of Cracks at Edges

with Edge Location Correction and Spatial filtering, using Signature Libraries



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Signature Library



DWG 2011 Slide 15

Hand Held Bolt Hole Scanner

- 1st generation product
- Removable cartridges with MWM-Arrays
- One rotation

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Plunge to find position



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GridStation HandHeld BSS DETERMINENT

Crack Detection / C-Scan Imaging for Bolt-holes Without bushings



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Rapid Risk Assessment from NDT Data

Component Adaptive Life Management (CALM) software



Cumulative probability distributions for crack size at Time t₁ Cumulative probability distributions for crack size at Time t₂ Cumulative probability distributions for cycles remaining to reach critical crack size (0.08 in.)

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CALM[™] Services

Component Adaptive Life Management

- POD curve generation for NDT & embedded sensors
- Risk assessment & RUL estimation

6/2/20

CALM

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C-Scans

Page

TANK B

Track Track Track Track Track

GRIDSTATION? -Report

Fleet transition support

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Model 8000

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FA-43

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CALM

Probe: FA57 Gendotation Version: 4.12x3 - JENTEK Test Release Almosthyn Version: 1, 0, 0, 0 (May 27 2010)

C/Uentek/Sess C/Uentek/Sess

GridStation Configuration Data

Algorithm Configuration Data

Application data

Analysis grid set Calibration grid set

Analysis Frequency: Norm Window Min X Value Norm Window Min X Value Analysis Area Min X Value Analysis Area Min X Value Analysis Area Min Channel Onalysis Area Max Channel Diago Filter Signature File Pittered Threshol

Component Metadata Aircraft Senial number Component Component serial number Operator Date

Time Temperature ('F) Relative Humidity

Compo

Results

JENTEK Instrument JENTEK Instrument Berial

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ent surface trea

0.4776

0.6698

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Sensor Sensor Serial Number Material

se Scan Data File

Instrument Probe:

After market decision support

CALM NDT REPORT

Stage t





Fatigue Specimen and Scanner for Signature Library Generation

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IN718 MWM-Array Fatigue Coupon



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Optional Difference Imaging or Baseline Subtraction

Improves Signal-to-Noise Levels to Reliably Detect Smaller Cracks



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A514 Grade B Steel Results







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Patents Issued and Pending

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